# MRS BULLETIN

Serving the International Materials Research Community

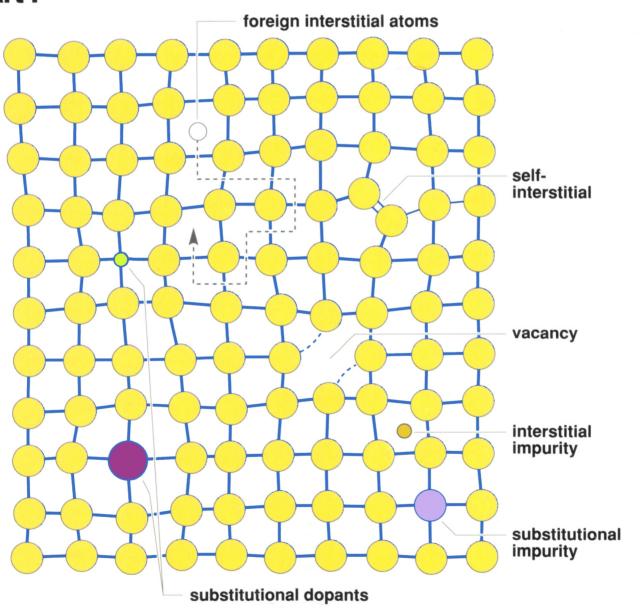
A Publication of the Materials Research Society

November 1991, Volume XVI, No. 11



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## MRS BULLETIN

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## POINT DEFECTS PART I

Point Defects in Materials
Part I: Behavior and
Characteristics in Different
Material Classes

D.N. Seidman and D. Shi, Guest Editors

33 Vacancies and Self-Interstitials

H.B. Huntington

38 Defects in Ceramic Oxides
A.S. Nowick

42 Point Defects and Diffusion in Semiconductors

U.M. Gösele and T.Y. Tan

47 Defects and Diffusion in Amorphous Alloys

R.S. Averback

54 Defects in High T<sub>c</sub> Cuprate Superconductors

Y. Zhu, J. Tafto, and M. Suenaga

#### **FEATURE**

63 Workshop Identifies Scientific, Commercial Opportunities for Future Thin Film Research and Technology

R.P.H. Chang and J.M. Poate

## INTERNATIONAL UNION OF MATERIALS RESEARCH SOCIETIES

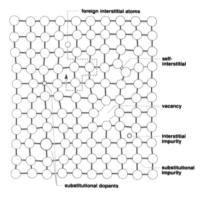
70 C-MRS Builds on Past Efforts to Form New Society

#### **MRS NEWS**

- 72 Geballe Receives Von Hippel Award
- 73 MRS Medals Go To Meyerson and Somiya
- 74 Graduate Finalists Compete for Awards at 1991 MRS Fall Meeting
- 75 Bromley to Address 1991 MRS Fall Meeting
- 79 MRS Members Elect 1992 Officers, Councillors
- 79 MRS Establishes David Turnbull Lectureship

#### **DEPARTMENTS**

- 6 Material Matters
- 11 Research/Researchers
- 22 From Washington
- 27 Resources
- 77 Advertisers in This Issue
- 78 Journal of Materials Research
- 84 Upcoming Conferences
- **86** Historical Note
- 88 Calendar
- 94 Classified
- 96 Posterminaries



**ON THE COVER:** Schematic, two-dimensional representation shows various types of intrinsic and extrinsic point defects that could be present in an elemental semiconductor crystal such as silicon. For more information on this topic, see "Point Defects and Diffusion in Semiconductors" by U.M. Gösele and T.Y. Tan on p. 42.

## IRISI BULLETI

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The Materials Research Society (MRS), a nonprofit scientific association founded in 1973, promotes interdisciplinary goal-oriented basic research on materials of technological importance. Membership in the Society includes more than 10,000 scientists, engineers, and research managers from industrial, government, and university research laboratories in the United States and more than 40 countries.

The Society's interdisciplinary approach differs from that of single-discipline profes-sional societies because it promotes information exchange across the many technical fields touching materials development. MRS sponsors two major international annual meetings encompassing approximately 50 topical symposia, and also sponsors numerous single-topic scientific meetings. The Society recognizes professional and technical excellence, conducts short courses, and fosters technical interaction in local geographic regions through Sections and University Chapters.

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MRS publishes symposium proceedings, MRS Bulletin, Journal of Materials Research, and other publications related to current research activities.

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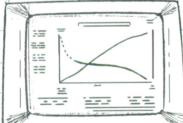
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